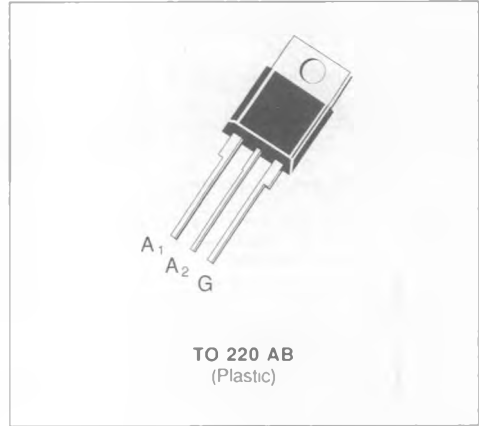




TRIACS

- GLASS PASSIVATED CHIP
- I_{GT} SPECIFIED IN FOUR QUADRANTS



DESCRIPTION

New range suited for applications such as phase control and static switching.

ABSOLUTE RATINGS (limiting values)

Symbol	Parameter		Value	Unit
$I_{T(RMS)}$	RMS on-state Current (360° conduction angle)	$T_C = 75^\circ C$	25	A
I_{TSM}	Non Repetitive Surge Peak on-state Current (T_J initial = $25^\circ C$ - Half sine wave)	$t = 8.3$ ms	210	A
		$t = 10$ ms	200	
I^2t	I^2t Value for Fusing	$t = 10$ ms	200	A^2s
di/dt	Critical Rate of Rise of on-state Current (1)	Repetitive $F = 50$ Hz	10	A/ μs
		Non Repetitive	50	
T_{stg} T_J	Storage and Operating Junction Temperature Range		- 40 to 150	$^\circ C$
			- 40 to 125	C

Symbol	Parameter	BTB 24-					Unit
		200B	400B	600B	700B	800B	
V_{DRM}	Repetitive Peak off-state Voltage (2)	200	400	600	700	800	V

(1) $I_G = 1$ A $di/dt = 1$ A/ μs
(2) $T_J = 125^\circ C$.

THERMAL RESISTANCES

Symbol	Parameter	Value	Unit
$R_{th(j-a)}$	Junction to Ambient	60	C/W
$R_{th(j-c)}$ DC	Junction to Case for DC	1.97	C/W
$R_{th(j-c)}$ AC	Junction to Case for 360° Conduction Angle ($F = 50$ Hz)	1.48	C/W

GATE CHARACTERISTICS (maximum values)

$P_{GM} = 40 \text{ W}$ ($t_p = 10 \text{ }\mu\text{s}$)

$I_{GM} = 4 \text{ A}$ ($t_p = 10 \text{ }\mu\text{s}$)

$P_{G(AV)} = 1 \text{ W}$

$V_{GM} = 16 \text{ V}$ ($t_p = 10 \text{ }\mu\text{s}$)

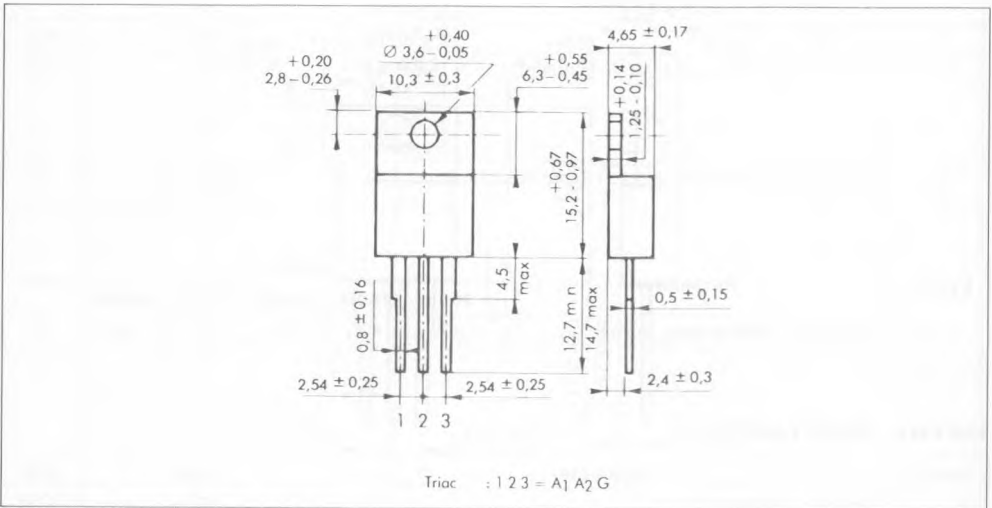
ELECTRICAL CHARACTERISTICS

Symbol	Test Conditions			Quadrants	Min.	Typ.	Max.	Unit
I_{GT}	$T_j = 25 \text{ }^\circ\text{C}$	$V_D = 12 \text{ V}$	$R_L = 33 \text{ }\Omega$	I-II-III			50	mA
				IV			100	
V_{GT}	$T_j = 25 \text{ }^\circ\text{C}$	$V_D = 12 \text{ V}$	$R_L = 33 \text{ }\Omega$	I-II-III-IV			1.5	V
V_{GD}	$T_j = 125 \text{ }^\circ\text{C}$	$V_D = V_{DRM}$	$R_L = 3.3 \text{ k}\Omega$	I-II-III-IV	0.2			V
I_H^*	$T_j = 25 \text{ }^\circ\text{C}$	$I_T = 100 \text{ mA}$	Gate Open				50	mA
I_L	$T_j = 25 \text{ }^\circ\text{C}$	$V_D = 12 \text{ V}$	Pulse Duration $> 20 \text{ }\mu\text{s}$	I-III-IV		50		mA
				II		100		
V_{TM}^*	$T_j = 25 \text{ }^\circ\text{C}$	$I_{TM} = 35 \text{ A}$	$t_p = 10 \text{ ms}$				1.8	V
I_{DRM}^*	V_{DRM} Specified						0.01	mA
							1	
dv/dt^*	$T_j = 125 \text{ }^\circ\text{C}$	Gate Open	Linear Slope up to $V_D = 67\% V_{DRM}$		250	500		V/ μs
$(dv/dt)_c^*$	$T_C = 75 \text{ }^\circ\text{C}$	$V_D = V_{DRM}$	$I_T = 35 \text{ A}$		10			V/ μs
t_{gt}	$T_j = 25 \text{ }^\circ\text{C}$	$V_D = V_{DRM}$	$I_T = 35 \text{ A}$	I-II-III-IV			2	μs

* For either polarity of electrode A_2 voltage with reference to electrode A_1 .

PACKAGE MECHANICAL DATA

TO 220 AB Plastic



Cooling method : by conduction (method C)

Marking : type number

Weight : 2 g.

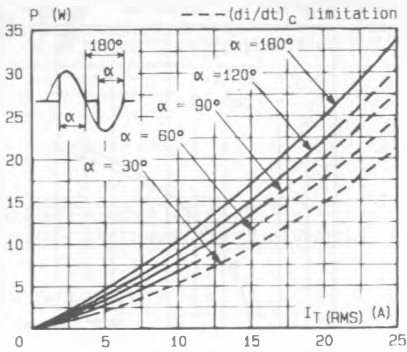


Fig. 1 - Maximum mean power dissipation versus RMS on-state current ($f = 60$ Hz).

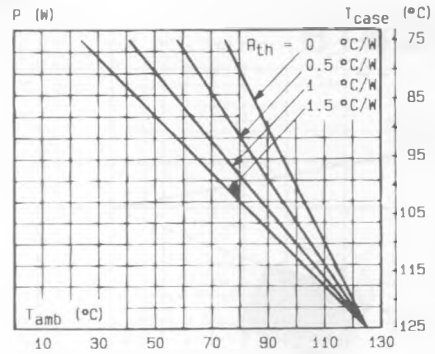


Fig. 2 - Correlation between maximum mean power dissipation and maximum allowable temperatures (T_{amb} and T_{case}) for different thermal resistances heatsink + contact.

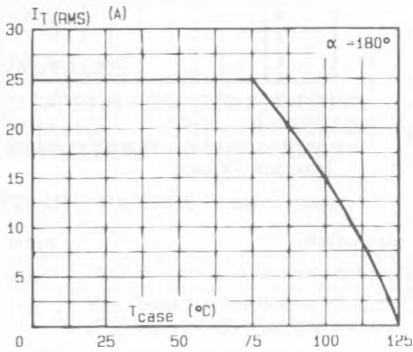


Fig. 3 - RMS on-state current versus case temperature.

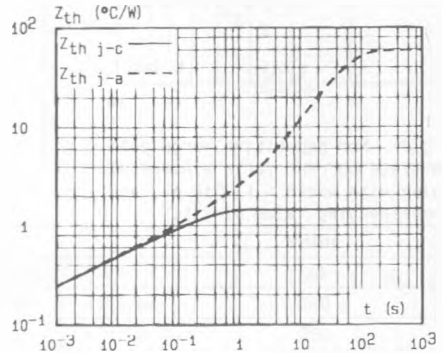


Fig. 4 - Thermal transient impedance junction to case and junction to ambient versus pulse duration.

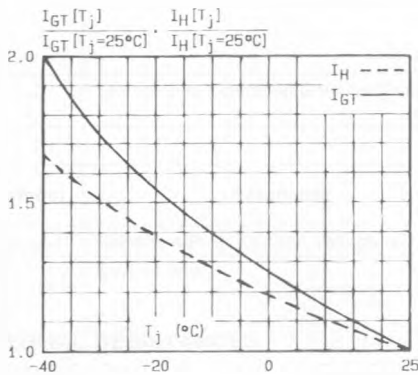


Fig. 5 - Relative variation of gate trigger current and holding current versus junction temperature.

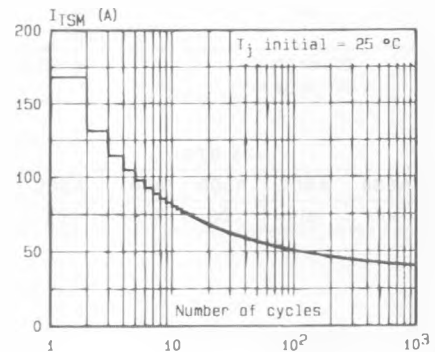


Fig. 6 - Non repetitive surge peak on-state current versus number of cycles.

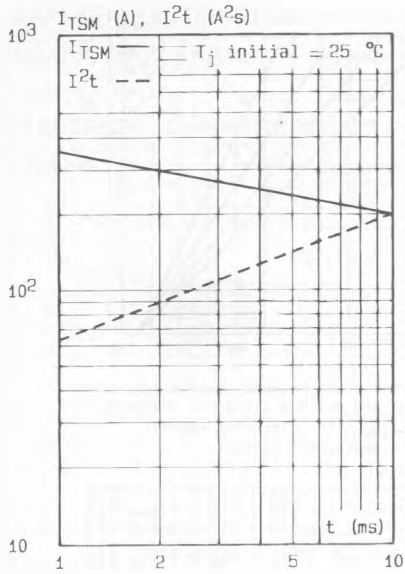


Fig.7 - Non repetitive surge peak on-state current for a sinusoidal pulse with width : $t \leq 10$ ms, and corresponding value of I^2t .

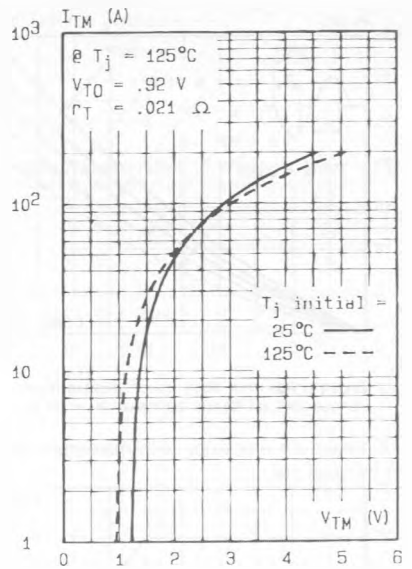


Fig.8 - Un-state characteristics (maximum values).